## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
09912188	BAILEY ET AL.
Examiner	Art Unit
Quoc, Tran A	2176

		SEARCHED		
Class		Subclass	Date	Examiner
	513		2/12/2007	QT
715				

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (USPAT, USPGPUB, JPO, USOCR, FPRS, EPO, DERWENT & IBM TDB)	2/19/2007	QT
NPL Search (ACM Digital Library)	2/19/2007	QT
Interference Search EAST (USPGPUB)	2/19/2007	QT
Inventors Searched Conducted- Considered Double Patent Rejection	2/19/2007	QT

•		INTERFERENCE SEA	ARCH	
Class		Subclass	Date	Examiner
715	513		2/19/2007	QT
705	37		2/19/2007	QT

-	Search Notes	-	

Application No.	Applicant(s)	
09/912,188	BAILEY ET AL.	
Examiner	Art Unit	
Quoc A Tran	2176	

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Class	Subclass	Date	Examiner
715	846	12/22/2004	D
715	513	12/22/2004	
707	9	12/22/2004	
705	27	12/22/2004	
705	37	10/22/2005	
709	219	10/22/2005	
		er,	
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INT	ERFERENC	E SEARCH	HED
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventor searcg check for double patent, US-PAT, US-PGPUB, EPO, JPO, Derwent, IBM_TDB, Internet search, Plus search, EIC	12/22/2004	D	
Personal Digests	12/22/2004		
US-PAT, US-PGPUB, EPO, JPO, Derwent, IBM_TDB DataBase (see Search Hlistory Printout)	10/22/2005		
IEEE DataBase (see search hiostory printout)	10/22/2005		